

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Takaki YOSHIDA : Confirmation Number:
Serial No.: : Group Art Unit:
Filed: January 06, 2004 : Examiner: Unknown
:
For: ERROR PORTION DETECTING METHOD AND LAYOUT METHOD FOR
SEMICONDUCTOR INTEGRATED CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

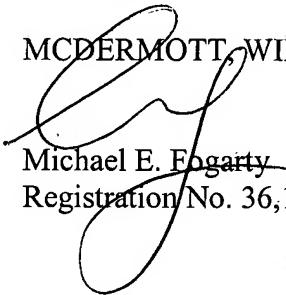
The relevance of Japanese Unexamined Patent Publication No. 7-239865 is discussed in the present specification.

Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY


Michael E. Fogarty
Registration No. 36,139

600 13th Street, N.W.
Washington, DC 20005-3096
(202) 756-8000 MEF:tlb
Facsimile: (202) 756-8087
Date: January 6, 2004

INFORMATION DISCLOSURE CITATION IN AN APPLICATION			ATTY. DOCKET NO. 60188-745		SERIAL NO.	
			APPLICANT Takaki YOSHIDA			
(PTO-1449)			FILING DATE January 06, 2004		GROUP	
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	US	6,311,147 B1	10/30/2001	Tuan et al.		
	US	6,453,443 B1	09/17/2002	Chen et al.		
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
	US					
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code-Number & Kind Codes (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation
						Yes
		JP 7-239865	09/12/1995	MATSUSHITA ELECTRIC IND CO LTD		(Japan w/English Abstract)
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
		Takaki YOSHIDA et al., "A New Approach for Low Power Scan Testing", ITC International Test Conference. Copyright 2003 IEEE				
EXAMINER			DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.